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Effect of substrate annealing temperature, vicinal-cut angle and miscut direction

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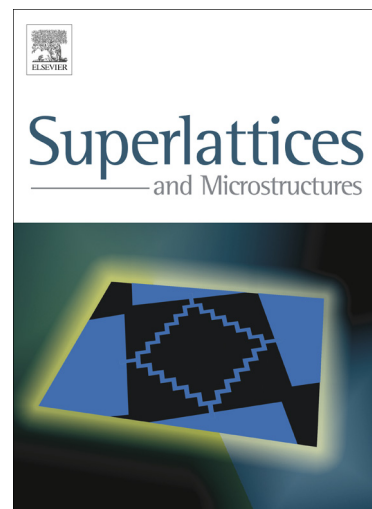
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**Characterization of ZnO thin film grown on c-plane substrates by
MO-CVD: Effect of substrate annealing temperature, vicinal-cut
angle and miscut direction.**

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